

11N90G-TA3-T-VB Datasheet

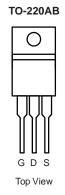
N-Channel 900V (D-S) Super Junction Power MOSFET

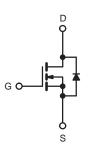
PRODUCT SUMMARY					
V _{DS} (V)	900				
$R_{DS(on)}(\Omega)$	$V_{GS} = 10 \text{ V}$	0.95			
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	900			
Gate-Source Voltage	V_{GS}	± 20	V		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}C$		7.0	А	
Continuous Diain Current	V_{GS} at 10 V $T_C = 100 ^{\circ}C$	ID	5.5		
Pulsed Drain Current ^a	I _{DM}	21			
Linear Derating Factor		1.5	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	770	mJ		
Repetitive Avalanche Currenta	I _{AR}	7.8	А		
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ		
Maximum Power Dissipation	T _C = 25 °C	P_{D}	190	W	
Peak Diode Recovery dV/dtc	dV/dt	2.0	V/ns		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	7	
Mounting Torque	6 22 or M2 oorow		10	lbf ⋅ in	
Mounting Torque	6-32 or M3 screw		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50$ V, starting $T_J=25$ °C, L=23 mH, $R_g=25$ Ω , $I_{AS}=7.8$ A (see fig. 12). c. $I_{SD}\leq7.8$ A, dl/dt \leq 140 A/ μ s, $V_{DD}\leq600$ V, $T_J\leq150$ °C.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	40			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65			

SPECIFICATIONS (T _J = 25 °C, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		900	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}		= 900 V, V _{GS} = 0 V /, V _{GS} = 0 V, T _J = 125 °C	-	-	100 500	μA	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 5.6 \text{ A}^b$	-	0.95	_	Ω	
Forward Transconductance	9fs	+	: 100 V, I _D = 5.6 A ^b	5.6	-	-	S	
Dynamic					L	L	l	
Input Capacitance	C _{iss}	V 0V		-	3100	_		
Output Capacitance	C _{oss}	1	$V_{GS} = 0 V$, $V_{DS} = 25 V$,		800	-	рF	
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	490	-		
Total Gate Charge	Qg			-	-	200		
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	24	nC	
Gate-Drain Charge	Q _{gd}	1			-	110		
Turn-On Delay Time	t _{d(on)}			-	19	-		
Rise Time	t _r	V _{DD} =	$V_{DD} = 400 \text{ V}, I_{D} = 5.6 \text{ A},$ $R_{g} = 6.2 \Omega, R_{D} = 52 \Omega$		38	-	- ns	
Turn-Off Delay Time	t _{d(off)}	R _g =			120	-		
Fall Time	t _f	see fig. 10 ^b		-	39	-		
Internal Drain Inductance	L _D	6 mm (0.25")	Between lead, 6 mm (0.25") from		5.0	-		
Internal Source Inductance	L _S	package and center of die contact		-	13	-	- nH	
Drain-Source Body Diode Characteristic	s						•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0		
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 5.6 A, V _{GS} = 0 V ^b		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 5.6 A, dl/dt = 100 A/μs ^b		-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is o			ninated b	y L _S and	L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

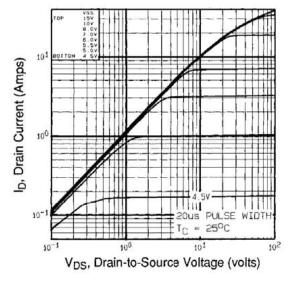


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

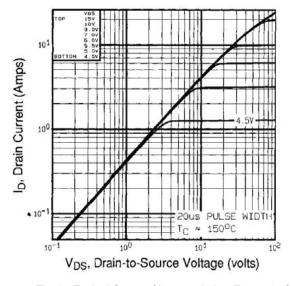


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

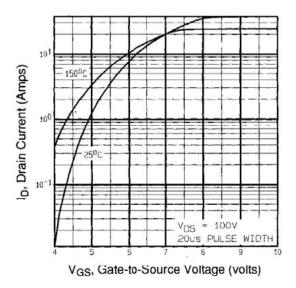


Fig. 3 - Typical Transfer Characteristics

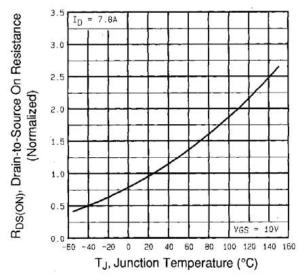


Fig. 4 - Normalized On-Resistance vs. Temperature



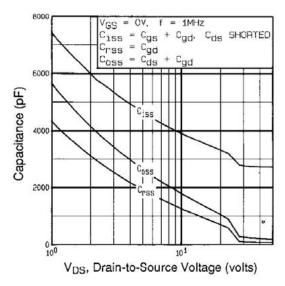


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

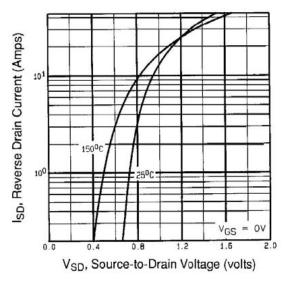


Fig. 7 - Typical Source-Drain Diode Forward Voltage

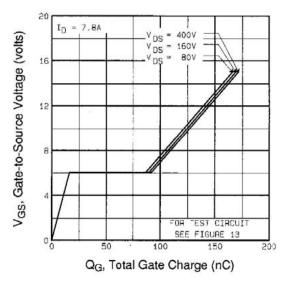


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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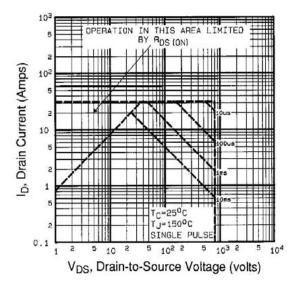


Fig. 8 - Maximum Safe Operating Area



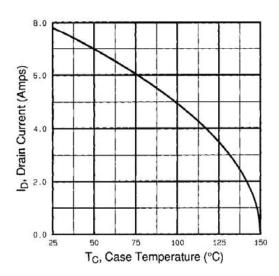


Fig. 9 - Maximum Drain Current vs. Case Temperature

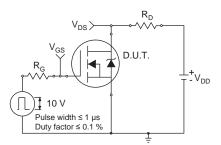


Fig. 10a - Switching Time Test Circuit

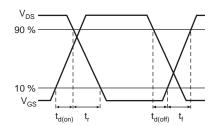


Fig. 10b - Switching Time Waveforms

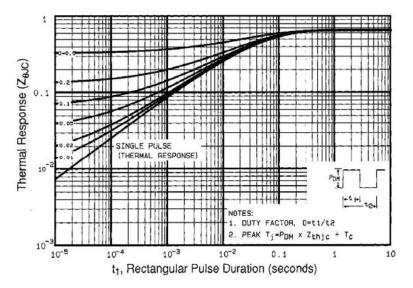


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



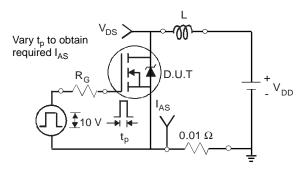


Fig. 12a - Unclamped Inductive Test Circuit

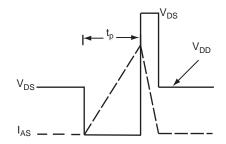


Fig. 12b - Unclamped Inductive Waveforms

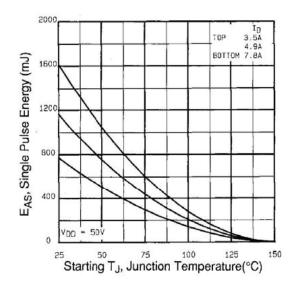


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

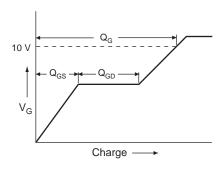


Fig. 13a - Basic Gate Charge Waveform

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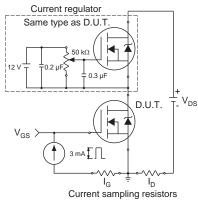
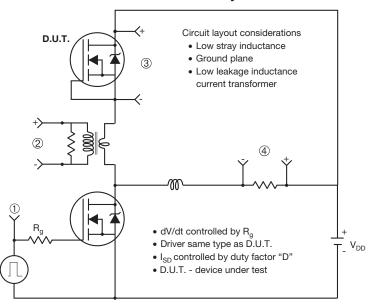


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



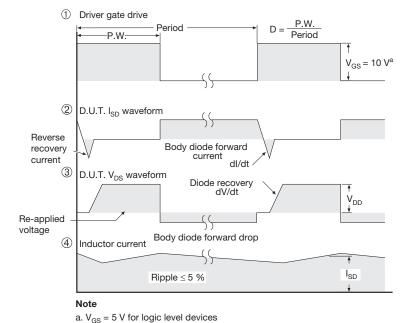
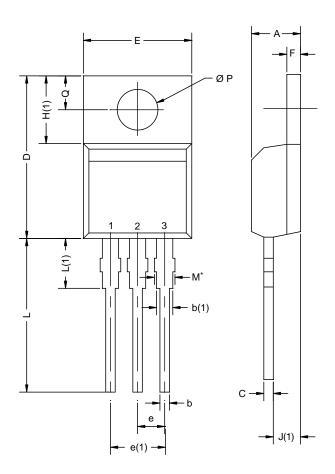


Fig. 14 - For N-Channel



TO-220AB



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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